FAIRCHILD

SEMICONDUCTOR TM

July 1989 Revised October 2000

# 74ACQ240 • 74ACTQ240 Quiet Series<sup>™</sup> Octal Buffer/Line Driver with 3-STATE Outputs

### **General Description**

The ACQ/ACTQ240 is an inverting octal buffer and line driver designed to be employed as a memory address driver, clock driver and bus oriented transmitter or receiver which provides improved PC board density. The ACQ/ ACTQ utilizes Fairchild's Quiet Series™ technology to guarantee quiet output switching and improve dynamic threshold performance. FACT Quiet Series™ features GTO™ output control and undershoot corrector in addition to a split ground bus for superior performance.

#### **Features**

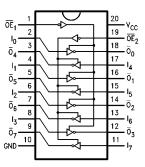
- I<sub>CC</sub> and I<sub>OZ</sub> reduced by 50%
- Guaranteed simultaneous switching noise level and dynamic threshold performance
- Guaranteed pin-to-pin skew AC performance
- Improved latch-up immunity
- Inverting 3-STATE outputs drive bus lines or buffer memory address registers
- Outputs source/sink 24 mA
- Faster prop delays than the standard ACT240

## **Ordering Code:**

Package Number	Package Description
M20B	20-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300 Wide
M20D	20-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide
N20A	20-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide
M20B	20-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300 Wide
M20D	20-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide
MQA20	20-Lead Quarter Size Outline Package (QSOP), JEDEC MO-137, 0.150 Wide
N20A	20-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide
	M20D N20A M20B M20D MQA20

Device also available in Tape and Reel. Specify by appending suffix letter "X" to the ordering code.

## **Connection Diagram**



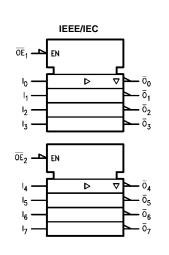
## **Pin Descriptions**

Pin Names	Description
$\overline{OE}_1, \overline{OE}_2$	3-STATE Output Enable Inputs
I <sub>0</sub> —I <sub>7</sub>	Inputs
$\overline{O}_0 - \overline{O}_7$	Outputs

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# 74ACQ240 • 74ACTQ240 Logic Symbol



## **Truth Tables**

Inp	uts	Outputs
OE <sub>1</sub>	I <sub>n</sub>	(Pins 12, 14, 16, 18)
L	L	н
L	н	L
н	х	Z
Inp	uts	Outputs
OE <sub>2</sub>	I <sub>n</sub>	(Pins 3, 5, 7, 9)
OE <sub>2</sub>	I <sub>n</sub> L	(Pins 3, 5, 7, 9) H
	I <sub>n</sub> L H	

H = HIGH Voltage Level L = LOW Voltage Level X = Immaterial Z = High Impedance

Absolute Maximum R	atings(Note 1)	Recommended Operati	ng
Supply Voltage (V <sub>CC</sub> )	-0.5V to +7.0V	Conditions	
DC Input Diode Current (I <sub>IK</sub> )		Supply Voltage (V <sub>CC</sub> )	
$V_{I} = -0.5V$	–20 mA	ACQ	2.0V to 6.0V
$V_I = V_{CC} + 0.5V$	+20 mA	ACTQ	4.5V to 5.5V
DC Input Voltage (V <sub>I</sub> )	$-0.5V$ to $V_{CC} + 0.5V$	Input Voltage (V <sub>I</sub> )	0V to V <sub>CC</sub>
DC Output Diode Current (I <sub>OK</sub> )		Output Voltage (V <sub>O</sub> )	0V to V <sub>CC</sub>
$V_{O} = -0.5V$	–20 mA	Operating Temperature (T <sub>A</sub> )	-40°C to +85°C
$V_{O} = V_{CC} + 0.5V$	+20 mA	Minimum Input Edge Rate $\Delta V / \Delta t$	
DC Output Voltage (V <sub>O</sub> )	$-0.5V$ to $V_{CC} + 0.5V$	ACQ Devices	
DC Output Source		$V_{IN}$ from 30% to 70% of $V_{CC}$	
or Sink Current (I <sub>O</sub> )	±50 mA	V <sub>CC</sub> @ 3.0V, 4.5V, 5.5V	125 mV/ns
DC V <sub>CC</sub> or Ground Current		Minimum Input Edge Rate $\Delta V/\Delta t$	
per Output Pin (I <sub>CC</sub> or I <sub>GND</sub> )	±50 mA	ACTQ Devices	
Storage Temperature (T <sub>STG</sub> )	$-65^{\circ}C$ to $+150^{\circ}C$	V <sub>IN</sub> from 0.8V to 2.0V	
DC Latch-Up Source or		V <sub>CC</sub> @ 4.5V, 5.5V	125 mV/ns
Sink Current	±300 mA	Note 1: Absolute maximum ratings are those value	
Junction Temperature (T <sub>J</sub> )		to the device may occur. The databook specificat out exception, to ensure that the system design	
PDIP	140°C	supply, temperature, and output/input loading var recommend operation of FACT™ circuits outside of	iables. Fairchild does not

# DC Electrical Characteristics for ACQ

Symbol	Parameter	V <sub>cc</sub>	<b>T</b> <sub>A</sub> = -	+25°C	$\textbf{T}_{\textbf{A}}=-40^{\circ}\textbf{C} \text{ to }+85^{\circ}\textbf{C}$	Units	Conditions	
Symbol	Minimum HIGH Level	(V)	Тур	Gua	aranteed Limits	Units	Conditions	
V <sub>IH</sub>		3.0	1.5	2.1	2.1		$V_{OUT} = 0.1V$	
	Input Voltage	4.5	2.25	3.15	3.15	V	or $V_{CC} - 0.1V$	
		5.5	2.75	3.85	3.85			
V <sub>IL</sub>	Maximum LOW Level	3.0	1.5	0.9	0.9		$V_{OUT} = 0.1V$	
	Input Voltage	4.5	2.25	1.35	1.35	V	or $V_{CC} - 0.1V$	
		5.5	2.75	1.65	1.65			
V <sub>OH</sub>	Minimum HIGH Level	3.0	2.99	2.9	2.9			
	Output Voltage	4.5	4.49	4.4	4.4	V	$I_{OUT} = -50 \ \mu A$	
		5.5	5.49	5.4	5.4			
							$V_{IN} = V_{IL} \text{ or } V_{IH}$	
		3.0		2.56	2.46		$I_{OH} = -12 \text{ mA}$	
		4.5		3.86	3.76	V	$I_{OH} = -24 \text{ mA}$	
		5.5		4.86	4.76		$I_{OH} = -24 \text{ mA}$ (Note 2	
V <sub>OL</sub>	Maximum LOW Level	3.0	0.002	0.1	0.1			
	Output Voltage	4.5	0.001	0.1	0.1	V	$I_{OUT} = 50 \ \mu A$	
		5.5	0.001	0.1	0.1			
							$V_{IN} = V_{IL} \text{ or } V_{IH}$	
		3.0		0.36	0.44		$I_{OL} = 12 \text{ mA}$	
		4.5		0.36	0.44	V	$I_{OL} = 24 \text{ mA}$	
		5.5		0.36	0.44		I <sub>OL</sub> = 24 mA (Note 2)	
I <sub>IN</sub>	Maximum Input	5.5		±0.1	±1.0	μA	$V_1 = V_{CC}$ , GND	
(Note 4)	Leakage Current	5.5		10.1	11.0	μΑ	VI - VCC, GND	
I <sub>OLD</sub>	Minimum Dynamic	5.5			75	mA	V <sub>OLD</sub> = 1.65V Max	
I <sub>OHD</sub>	Output Current (Note 3)	5.5			-75	mA	V <sub>OHD</sub> = 3.85V Min	
I <sub>CC</sub>	Maximum Quiescent	5.5		4.0	40.0	μA	$V_{IN} = V_{CC}$ or GND	
(Note 4)	Supply Current	5.5		4.0	40.0	μΑ	VIN - VCC OI GIVD	
I <sub>OZ</sub>	Maximum 3-STATE						$V_{I}$ (OE) = $V_{IL}$ , $V_{IH}$	
	Leakage Current	5.5		±0.25	±2.5	μA	$V_I = V_{CC}, GND$	
							$V_{O} = V_{CC}, GND$	

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## DC Electrical Characteristics for ACQ (Continued)

Symbol	Parameter	v <sub>cc</sub>	C T <sub>A</sub> = +25°C		$\textbf{T}_{\textbf{A}}=-40^{\circ}\textbf{C}$ to $+85^{\circ}\textbf{C}$	Units	Conditions	
Cymbol	r arameter	(V)	Тур	Gua	aranteed Limits	onita	Conditions	
V <sub>OLP</sub>	Quiet Output	5.0	1.1	1.5		V	Figures 1, 2	
	Maximum Dynamic V <sub>OL</sub>	5.0	1.1	1.5		v	(Note 5)(Note 6)	
V <sub>OLV</sub>	Quiet Output	5.0	-0.6	-1.2		V	Figures 1, 2	
	Minimum Dynamic V <sub>OL</sub>	5.0	-0.6	-1.2		v	(Note 5)(Note 6)	
V <sub>IHD</sub>	Minimum HIGH Level Dynamic Input Voltage	5.0	3.1	3.5		V	(Note 5)(Note 7)	
V <sub>ILD</sub>	Maximum LOW Level Dynamic Input Voltage	5.0	1.9	1.5		V	(Note 5)(Note 7)	

Note 2: All outputs loaded; thresholds on input associated with output under test. Note 3: Maximum test duration 2.0 ms, one output loaded at a time.

Note 5. Maximum test duration 2.0 ms, one output loaded at a time.

Note 4:  $I_{\rm IN}$  and  $I_{\rm CC}$  @ 3.0V are guaranteed to be less than or equal to the respective limit @ 5.5V  $V_{\rm CC}.$ 

Note 5: Plastic DIP package.

Note 6: Max number of outputs defined as (n). Data inputs are driven 0V to 5V. One output @ GND.

Note 7: Max number of data inputs (n) switching. (n –1) inputs switching 0V to 5V (ACQ). Input-under-test switching: 5V to threshold ( $V_{ILD}$ ), 0V to threshold ( $V_{ILD}$ ), f = 1 MHz.

## **DC Electrical Characteristics for ACTQ**

Symbol	Parameter	v <sub>cc</sub>	T <sub>A</sub> =	+25°C	$T_A = -40^{\circ}C$ to $+85^{\circ}C$	Units	Conditions	
Cymber	Farameter	(V)	Тур	Gu	aranteed Limits	Units	Conditions	
VIH	Minimum HIGH Level	4.5	1.5	2.0	2.0	V	$V_{OUT} = 0.1V$	
	Input Voltage	5.5	1.5	2.0	2.0	v	or $V_{CC} - 0.1V$	
VIL	Maximum LOW Level	4.5	1.5	0.8	0.8	V	$V_{OUT} = 0.1V$	
	Input Voltage	5.5	1.5	0.8	0.8	v	or $V_{CC} - 0.1V$	
V <sub>OH</sub>	Minimum HIGH Level	4.5	4.49	4.4	4.4	V	L 50 A	
	Output Voltage	5.5	5.49	5.4	5.4	v	$I_{OUT} = -50 \ \mu A$	
		4.5		3.86	3.76	V	$V_{IN} = V_{IL} \text{ or } V_{IH}$ $I_{OH} = -24 \text{ mA}$	
		5.5		4.86	4.76		I <sub>OH</sub> = -24 mA (Note 8)	
V <sub>OL</sub>	Maximum LOW Level	4.5	0.001	0.1	0.1	V		
	Output Voltage	5.5	0.001	0.1	0.1	v	$I_{OUT} = 50 \ \mu A$	
							$V_{IN} = V_{IL} \text{ or } V_{IH}$	
		4.5		0.36	0.44	V	I <sub>OL</sub> = 24 mA	
		5.5		0.36	0.44		I <sub>OL</sub> = 24 mA (Note 8)	
I <sub>IN</sub>	Maximum Input Leakage Current	5.5		±0.1	±1.0	μA	$V_I = V_{CC}, GND$	
I <sub>OZ</sub>	Maximum 3-STATE	5.5		±0.25	±2.5	μA	$V_I = V_{IL}, V_{IH}$	
	Leakage Current	5.5		10.25	12.5	μΛ	$V_O = V_{CC}$ , GND	
I <sub>CCT</sub>	Maximum I <sub>CC</sub> /Input	5.5	0.6		1.5	mA	$V_I = V_{CC} - 2.1V$	
I <sub>OLD</sub>	Minimum Dynamic	5.5			75	mA	V <sub>OLD</sub> = 1.65V Max	
I <sub>OHD</sub>	Output Current (Note 9)	5.5			-75	mA	V <sub>OHD</sub> = 3.85V Min	
I <sub>CC</sub>	Maximum Quiescent Supply Current	5.5		4.0	40.0	μΑ	$V_{IN} = V_{CC}$ or GND	
V <sub>OLP</sub>	Quiet Output Maximum Dynamic V <sub>OL</sub>	5.0	1.1	1.5		V	Figures 1, 2 (Note 10)(Note 11)	
V <sub>OLV</sub>	Quiet Output Minimum	FO	0.0	10		V	Figures 1, 2	
	Dynamic V <sub>OL</sub>	5.0	-0.6	-1.2		v	(Note 10)(Note 11)	
V <sub>IHD</sub>	Minimum HIGH Level Dynamic Input Voltage	5.0	1.9	2.2		V	(Note 10)(Note 12)	
VILD	Maximum LOW Level Dynamic Input Voltage	5.0	1.2	0.8	1	V	(Note 10)(Note 12)	

Note 8: All outputs loaded; thresholds on input associated with output under test.

Note 9: Maximum test duration 2.0 ms, one output loaded at a time.

Note 10: Plastic DIP package.

Note 11: Max number of Data Inputs defined as (n). n–1 Data Inputs are driven 0V to 3V. One Data Input @  $V_{IN} = GND$ .

Note 12: Max number of Data Inputs (n) switching. (n–1) Inputs switching 0V to 3V (ACTQ). Input-under-test switching: 3V to threshold ( $V_{ILD}$ ), 0V to threshold ( $V_{ILD}$ ), f = 1 MHz.

## **AC Electrical Characteristics for ACQ**

Symbol Parameter		$V_{CC}$ $T_A = +25^{\circ}C$ (V) $C_L = 50 \text{ pF}$				$T_{A} = -40^{\circ}$ $C_{I} =$	Units	
	(Note 13)	Min	Тур	Max	Min	Max	onno	
t <sub>PHL</sub>	Propagation Delay	3.3	2.0	7.0	10.0	2.0	10.5	
t <sub>PLH</sub>	Data to Output	5.0	1.5	5.0	6.5	1.5	7.0	ns
t <sub>PZL</sub>	Output Enable Time	3.3	2.5	8.0	12.0	2.5	12.5	
t <sub>PZH</sub>		5.0	1.5	5.5	8.0	1.5	8.5	ns
t <sub>PHZ</sub>	Output Disable Time	3.3	1.0	8.5	13.5	1.0	14.0	
t <sub>PLZ</sub>		5.0	1.0	6.0	9.0	1.0	9.5	ns
t <sub>OSHL</sub>	Output to Output Skew	3.3		1.0	1.5		1.5	
t <sub>OSLH</sub>	Data to Output (Note 14)	5.0		0.5	1.0		1.0	ns

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Note 13: Voltage Range 5.0 is  $5.0V \pm 0.5V$ 

Voltage Range 3.3 is 3.3  $\pm$  0.3V.

Note 14: Skew is defined as the absolute value of the difference between the actual propagation delay for any two separate outputs of the same device. The specification applies to any outputs switching in the same direction, either HIGH-to-LOW (t<sub>OSHL</sub>) or LOW-to-HIGH (t<sub>OSLH</sub>). Parameter guaranteed by design.

## **AC Electrical Characteristics for ACTQ**

Symbol	Parameter	V <sub>CC</sub> (V)	T <sub>A</sub> = +25°C C <sub>L</sub> = 50 pF			T <sub>A</sub> = -40° C <sub>L</sub> =	Units	
		(Note 15)	Min	Тур	Max	Min	Max	
t <sub>PHL</sub>	Propagation Delay	5.0	1.5	5.5	7.0	1.5	7.5	ns
t <sub>PLH</sub>	Data to Output	5.0	1.5	0.0	7.0	1.5	7.5	113
t <sub>PZL</sub> , t <sub>PZH</sub>	Output Enable Time	5.0	1.5	6.5	8.5	1.5	9.0	ns
t <sub>PHZ</sub> , t <sub>PLZ</sub>	Output Disable Time	5.0	1.0	7.0	9.5	1.0	10.0	ns
t <sub>OSHL</sub>	Output to Output Skew	5.0		0.5	1.0		1.0	ns
t <sub>OSLH</sub>	Data to Output (Note 16)	5.0		0.5	1.0		1.0	115

Note 15: Voltage Range 5.0 is  $5.0V \pm 0.5V$ 

Note 16: Skew is defined as the absolute value of the difference between the actual propagation delay for any two separate outputs of the same device. The specification applies to any outputs switching in the same direction, either HIGH-to-LOW (t<sub>OSHL</sub>) or LOW-to-HIGH (t<sub>OSLH</sub>). Parameter guaranteed by design.

## Capacitance

Symbol	Parameter	Тур	Units	Conditions
CIN	Input Capacitance	4.5	pF	V <sub>CC</sub> = OPEN
C <sub>PD</sub>	Power Dissipation Capacitance	70	pF	$V_{CC} = 5.0V$

#### **FACT Noise Characteristics**

The setup of a noise characteristics measurement is critical to the accuracy and repeatability of the tests. The following is a brief description of the setup used to measure the noise characteristics of FACT.

Equipment:

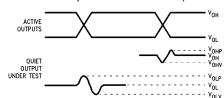
Hewlett Packard Model 8180A Word Generator

PC-163A Test Fixture

Tektronics Model 7854 Oscilloscope

Procedure:

- 1. Verify Test Fixture Loading: Standard Load 50 pF,  $500\Omega.$
- Deskew the HFS generator so that no two channels have greater than 150 ps skew between them. This requires that the oscilloscope be deskewed first. It is important to deskew the HFS generator channels before testing. This will ensure that the outputs switch simultaneously.
- Terminate all inputs and outputs to ensure proper loading of the outputs and that the input levels are at the correct voltage.
- Set the HFS generator to toggle all but one output at a frequency of 1 MHz. Greater frequencies will increase DUT heating and affect the results of the measurement.
- Set the HFS generator input levels at 0V LOW and 3V HIGH for ACT devices and 0V LOW and 5V HIGH for AC devices. Verify levels with an oscilloscope.



Note 17:  $V_{OHV}$  and  $V_{OLP}$  are measured with respect to ground reference Note 18: Input pulses have the following characteristics: f = 1 MHz,  $t_r = 3 \text{ ns}$ ,  $t_f = 3 \text{ ns}$ , skew < 150 ps.

FIGURE 1. Quiet Output Noise Voltage Waveforms

V<sub>OLP</sub>/V<sub>OLV</sub> and V<sub>OHP</sub>/V<sub>OHV</sub>:

- Determine the quiet output pin that demonstrates the greatest noise levels. The worst case pin will usually be the furthest from the ground pin. Monitor the output voltages using a  $50\Omega$  coaxial cable plugged into a standard SMB type connector on the test fixture. Do not use an active FET probe.
- Measure V<sub>OLP</sub> and V<sub>OLV</sub> on the quiet output during the worst case transition for active and enable. Measure V<sub>OHP</sub> and V<sub>OHV</sub> on the quiet output during the worst case active and enable transition.
- Verify that the GND reference recorded on the oscilloscope has not drifted to ensure the accuracy and repeatability of the measurements.

V<sub>ILD</sub> and V<sub>IHD</sub>:

- Monitor one of the switching outputs using a  $50\Omega$  coaxial cable plugged into a standard SMB type connector on the test fixture. Do not use an active FET probe.
- First increase the input LOW voltage level, V<sub>IL</sub>, until the output begins to oscillate or steps out a min of 2 ns. Oscillation is defined as noise on the output LOW level that exceeds V<sub>IL</sub> limits, or on output HIGH levels that exceed V<sub>IH</sub> limits. The input LOW voltage level at which oscillation occurs is defined as V<sub>ILD</sub>.
- Next decrease the input HIGH voltage level, V<sub>IH</sub>, until the output begins to oscillate or steps out a min of 2 ns. Oscillation is defined as noise on the output LOW level that exceeds V<sub>IL</sub> limits, or on output HIGH levels that exceed V<sub>IH</sub> limits. The input HIGH voltage level at which oscillation occurs is defined as V<sub>IHD</sub>.
- Verify that the GND reference recorded on the oscilloscope has not drifted to ensure the accuracy and repeatability of the measurements.

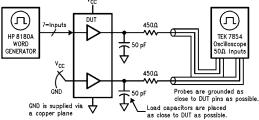


FIGURE 2. Simultaneous Switching Test Circuit

